

IRFP250, IRFP251, IRFP252, IRFP253

27A and 33A, 150V and 200V, 0.085 and 0.12 Ohm,
N-Channel Power MOSFETs

January 1998

Features

- 27A and 33A, 150V and 200V
- $r_{DS(ON)} = 0.085\Omega$ and 0.120Ω
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Ordering Information

PART NUMBER	PACKAGE	BRAND
IRFP250	TO-247	IRFP250
IRFP251	TO-247	IRFP251
IRFP252	TO-247	IRFP252
IRFP253	TO-247	IRFP253

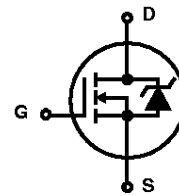
NOTE: When ordering, use the entire part number.

Description

These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

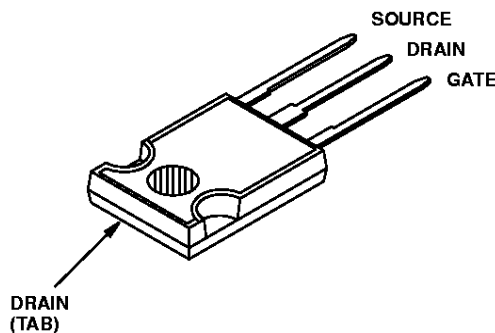
Formerly developmental type TA9295.

Symbol



Packaging

JEDEC STYLE TO-247



IRFP250, IRFP251, IRFP252, IRFP253

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

	IRFP250	IRFP251	IRFP252	IRFP253	UNITS
Drain to Source Voltage (Note 1) V_{DS}	200	150	200	150	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1) V_{DGR}	200	150	200	150	V
Continuous Drain Current I_D	33	33	27	27	A
$T_C = 100^\circ\text{C}$ I_D	21	21	17	17	A
Pulsed Drain Current (Note 3) I_{DM}	130	130	110	110	A
Gate to Source Voltage V_{GS}	± 20	± 20	± 20	± 20	V
Maximum Power Dissipation P_D	180	180	180	180	W
Linear Derating Factor	1.44	1.44	1.44	1.44	W/ $^\circ\text{C}$
Single Pulse Avalanche Energy Rating (Note 4) E_{AS}	810	810	810	810	mJ
Operating and Storage Temperature T_J, T_{STG}	-55 to 150	-55 to 150	-55 to 150	-55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering					
Leads at 0.063in (1.6mm) from Case for 10s T_L	300	300	300	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 T_{pk}	260	260	260	260	$^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

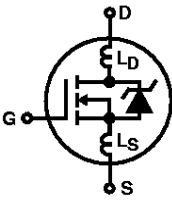
- $T_J = 25^\circ\text{C}$ to 125°C .

Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

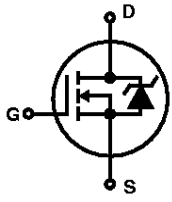
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage IRFP250, IRFP252	BV_{DSS}	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$, (Figure 10)	200	-	-	V
			IRFP251, IRFP253	150	-	-
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2.0	-	4.0	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}$	-	-	25	μA
		$V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}, T_C = 125^\circ\text{C}$	-	-	250	μA
On-State Drain Current (Note 2) IRFP250, IRFP251	$I_{D(ON)}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, V_{GS} = 10\text{V}$	33	-	-	A
			IRFP252, IRFP253	27	-	-
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
Drain to Source On Resistance (Note 2) IRFP250, IRFP251	$r_{DS(ON)}$	$I_D = 17\text{A}, V_{GS} = 10\text{V}$, (Figures 8, 9)	-	0.07	0.085	Ω
			IRFP252, IRFP253	-	0.09	0.120
Forward Transconductance (Note 2)	g_{fs}	$V_{DS} \geq 50\text{V}, I_D = 17\text{A}$, (Figure 12)	13	19	-	S
Turn-On Delay Time	$t_{d(ON)}$	$V_{DD} = 100\text{V}, I_D = 30\text{A}, R_G = 6.2\Omega, V_{GS} = 10\text{V}, R_L = 3.2\Omega$, (Figures 17, 18) MOSFET Switching Times are Essentially Independent of Operating Temperature	-	18	30	ns
Rise Time	t_r		-	125	180	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	70	100	ns
Fall Time	t_f		-	80	120	ns
Total Gate Charge (Gate to Source + Gate to Drain)	$Q_g(\text{TOT})$		$V_{GS} = 10\text{V}, I_D = 30\text{A}, V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, I_{G(\text{REF})} = 1.5\text{mA}$, (Figures 14, 19, 20) Gate Charge is Essentially Independent of Operating Temperature	-	79	120
Gate to Source Charge	Q_{gs}		-	12	-	nC
Gate to Drain "Miller" Charge	Q_{gd}		-	42	-	nC

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Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Input Capacitance	C_{ISS}	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$, (Figure 11)		-	2000	-	pF
Output Capacitance	C_{OSS}			-	800	-	pF
Reverse Transfer Capacitance	C_{RSS}			-	300	-	pF
Internal Drain Inductance	L_D	Measured From the Contact Screw on Header Closer to Source and Gate Pins to Center of Die	Modified MOSFET Symbol Showing the Internal Device Inductances 	-	5.0	-	nH
Internal Source Inductance	L_S	Measured From the Source Lead, 6.0mm (0.25in) From Header to Source Bonding Pad		-	12.5	-	nH
Thermal Resistance, Junction to Case	$R_{\theta JC}$			-	-	0.70	$^\circ\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	Free Air Operation		-	-	30	$^\circ\text{C/W}$

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I_{SD}	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Rectifier 	-	-	33	A	
Pulse Source to Drain Current (Note 3)	I_{SDM}		-	-	130	A	
Source to Drain Diode Voltage (Note 2)	V_{SD}	$T_J = 25^\circ\text{C}$, $I_{SD} = 33\text{A}$, $V_{GS} = 0\text{V}$, (Figure 13)		-	-	2.0	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_{SD} = 30\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$		140	-	630	ns
Reverse Recovery Charge	Q_{RR}	$T_J = 25^\circ\text{C}$, $I_{SD} = 30\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$		1.8	-	8.1	μC

NOTES:

2. Pulse test: pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. Repetitive rating: pulse width limited by maximum junction temperature. See Transient Thermal Impedance curve (Figure 3).
4. $V_{DD} = 50\text{V}$, starting $T_J = 25^\circ\text{C}$, $L = 1.1\text{mH}$, $R_G = 50\Omega$, peak $I_{AS} = 33\text{A}$. (Figures 15, 16)

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Typical Performance Curves Unless Otherwise Specified

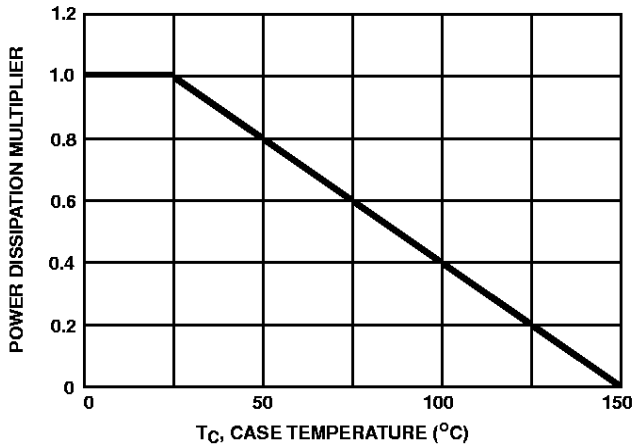


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

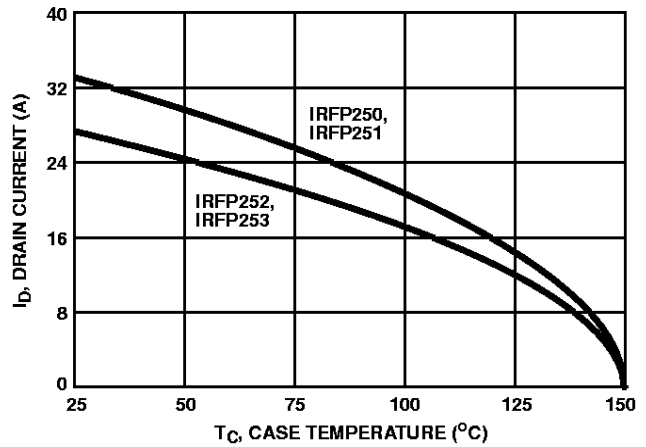


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

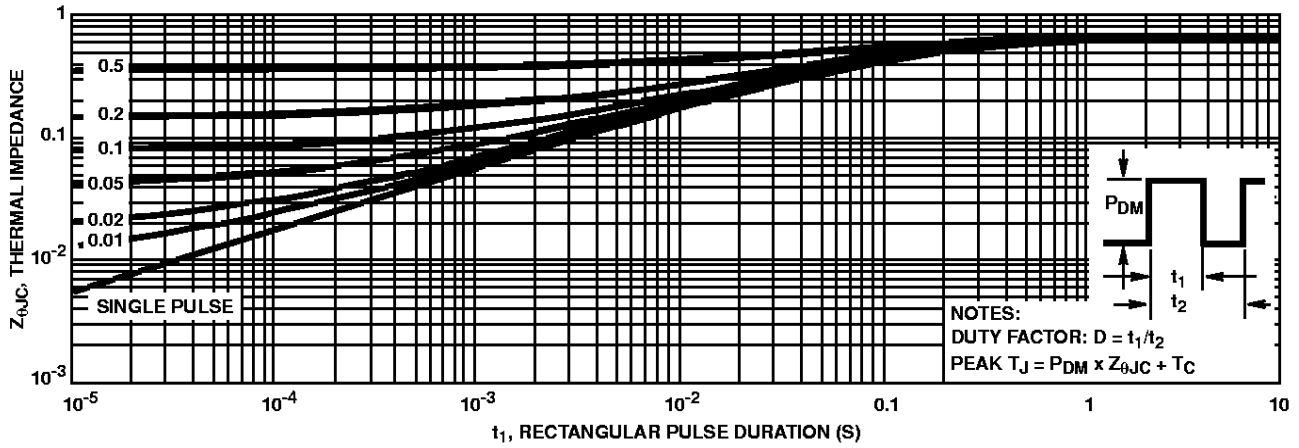


FIGURE 3. MAXIMUM TRANSIENT THERMAL IMPEDANCE

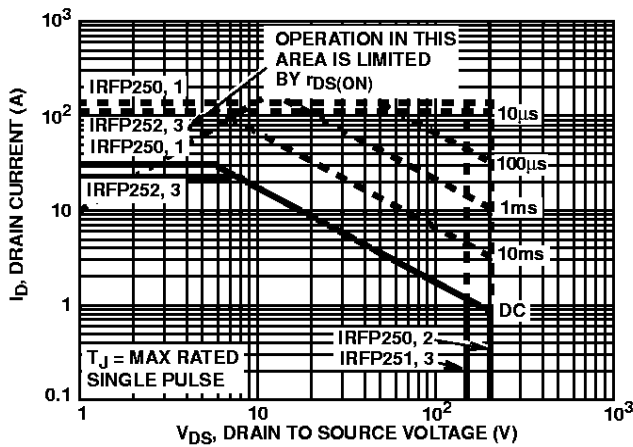


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

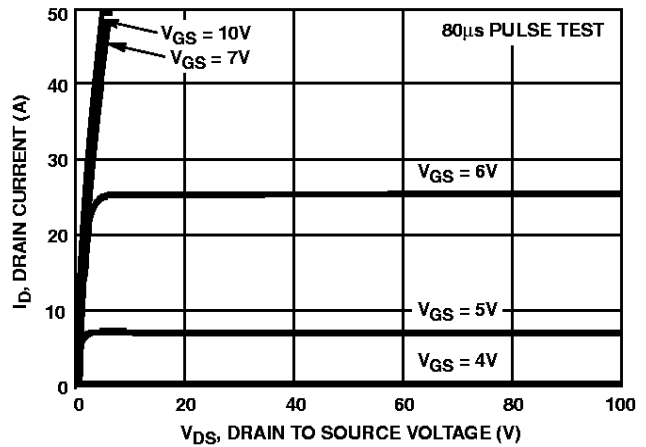


FIGURE 5. OUTPUT CHARACTERISTICS

Typical Performance Curves Unless Otherwise Specified (Continued)

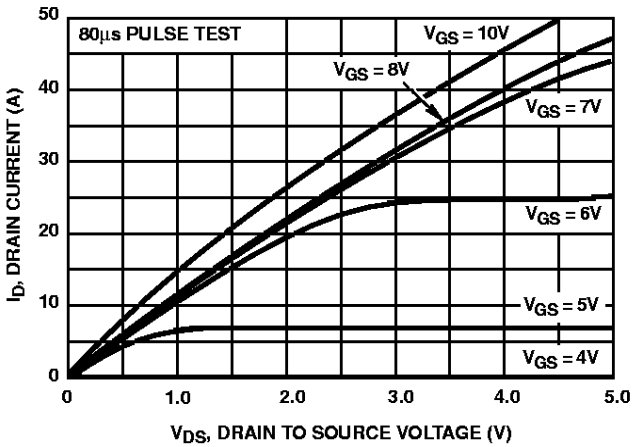


FIGURE 6. SATURATION CHARACTERISTICS

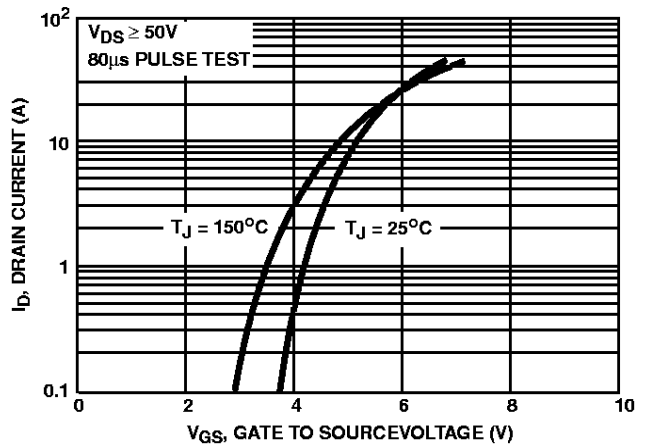
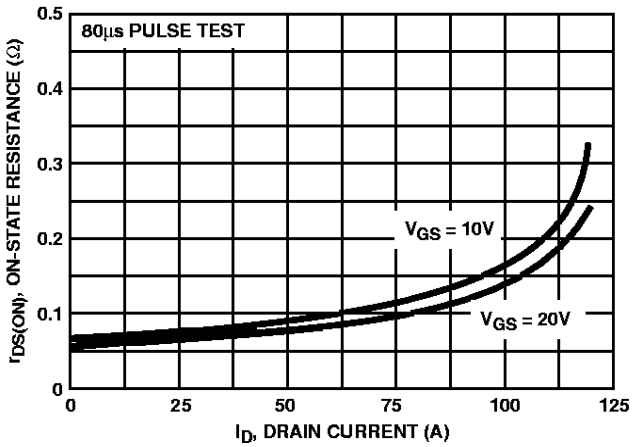


FIGURE 7. TRANSFER CHARACTERISTICS



NOTE: Heating effect of 2µs pulse is minimal.
FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

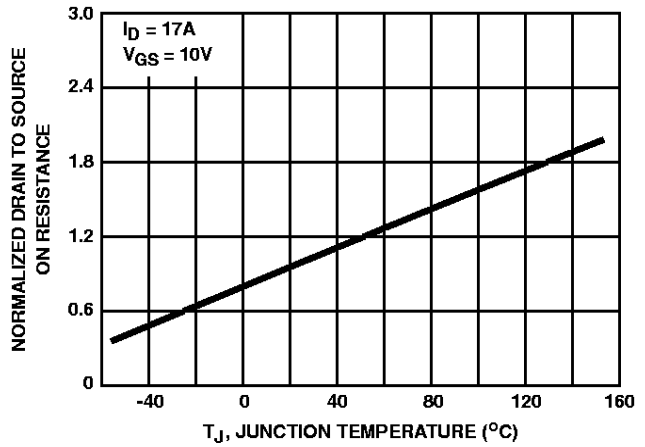


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

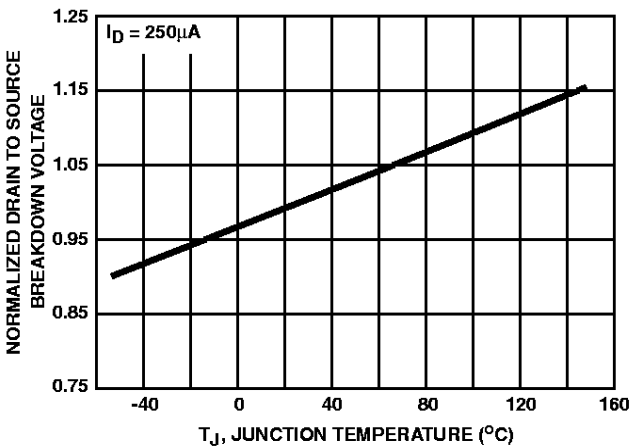


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

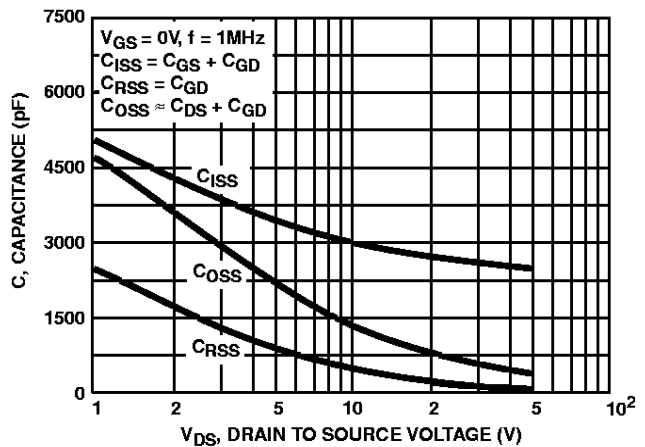


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

Typical Performance Curves Unless Otherwise Specified (Continued)

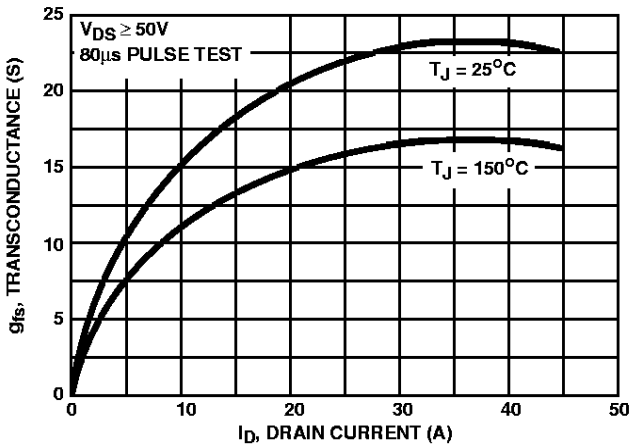


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

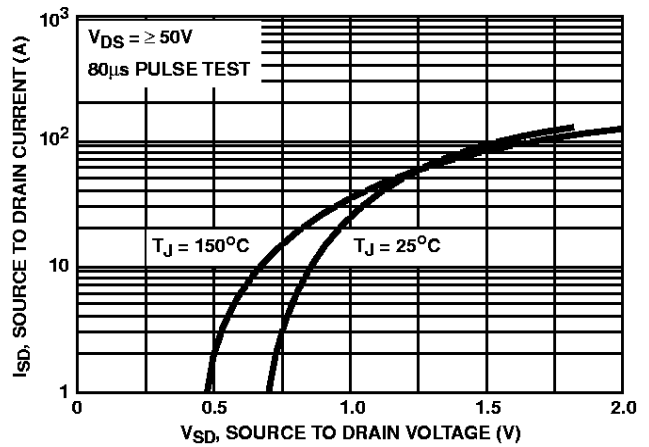


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

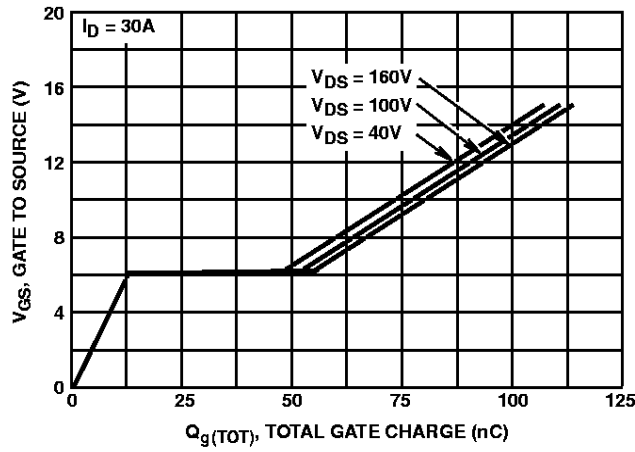


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

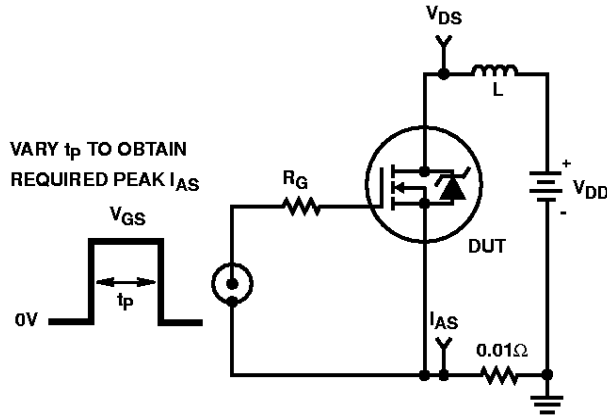


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

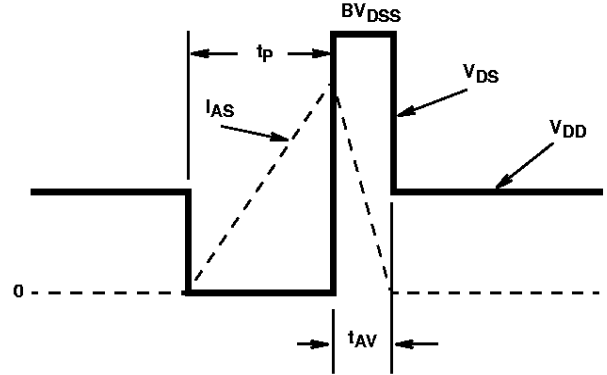


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

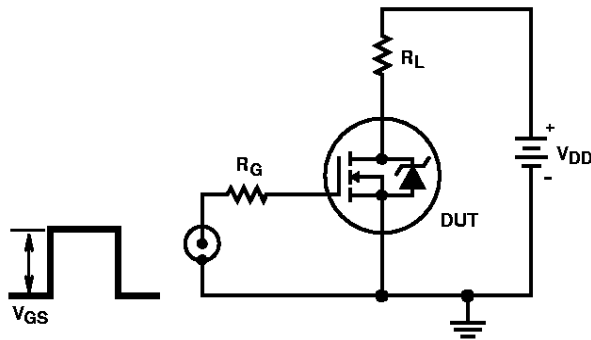


FIGURE 17. SWITCHING TIME TEST CIRCUIT

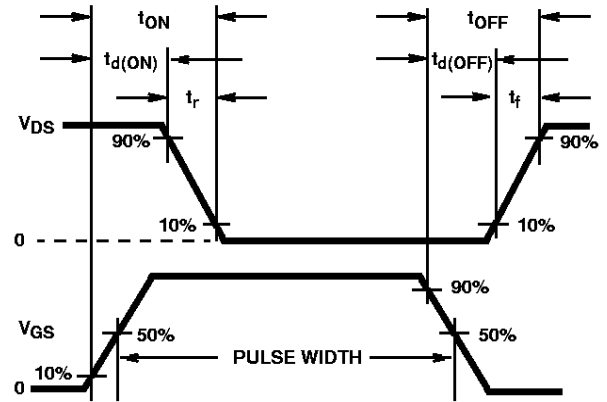


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

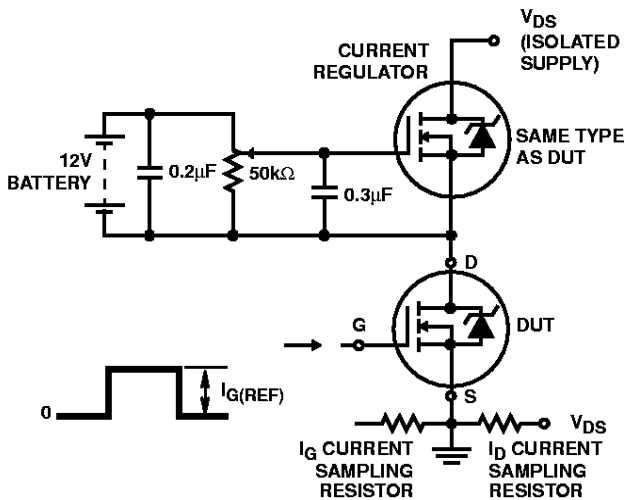


FIGURE 19. GATE CHARGE TEST CIRCUIT

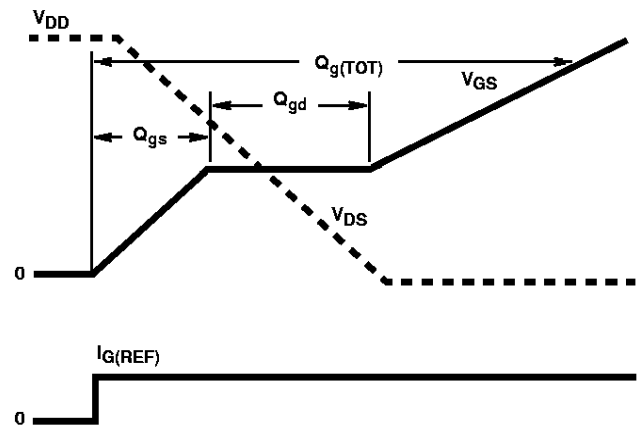


FIGURE 20. GATE CHARGE WAVEFORMS